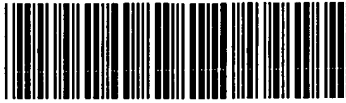


**Search Notes**

Application/Control No.

10/600,310

Examiner

Soon D. Hyun

Applicant(s)/Patent under  
Reexamination

YEH ET AL.

Art Unit

2616

**SEARCHED**

Class	Subclass	Date	Examiner

**INTERFERENCE SEARCHED**

Class	Subclass	Date	Examiner
interference serach-see printout		3/27/2007	HY

**SEARCH NOTES  
(INCLUDING SEARCH STRATEGY)**

	DATE	EXMR
370/203- 211;375/146,147,235,261,267,299,34 7;text search only-see search history printout	3/27/2007	HY